## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No	
Filing Date	July 24, 2001
	Segal et al
	Honeywell International Inc
	1742
	H. Wilkins II
Attorney's Docket No	30-5004-DIV2
Angular Extrusion	ture of Alloys Utilizing Equal Channe
1 mile	<i>∴</i>

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## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Mail Stop RCE

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

From:

Jennifer J. Taylor, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)

Wells St. John P.S.

601 W. First Avenue, Suite 1300

Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449 and copies of which are attached.

Citation of these references is respectfully requested.

Respectfully submitted,

Datad

By:

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er J. Taylor,

Æea. No. 48.7

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 30-5004(4015) DIV2

APPLICANT Vladimir Segal et al.

SERIAL NO. 09/912,652

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

FILING DATE July 24, 2001

U.S. PATENT DOCUMENTS

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*Examiner *Initial		Document Number	Date	Name	Class	Subclass		Filing Date If Appropriate			
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EXAMINER		DATE CONSIDERE	CD								

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of

this form with next communication to applicant.

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